

**Search Notes****Application/Control No.**

10/532,632

**Examiner**

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**Applicant(s)/Patent under Reexamination**

CHEN ET AL.

**Art Unit**

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	299	1/31/2007	EB
375	267	1/31/2007	EB
375	150	1/31/2007	EB
375	349	1/31/2007	EB
375	347	1/31/2007	EB
375	295	1/31/2007	EB
370	335	1/31/2007	EB

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	1/31/2007	EB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner